

Search Notes

Application/Control No.

10/521,147

Examiner

Benny Lee

Applicant(s)/Patent under
Reexamination

FURUTA, TAKESHI

Art Unit

2817

SEARCHED

Class	Subclass	Date	Examiner
333	101,103, 104,262	3/12/2007	BTL
Rsch	above	8/20/2007	BTL

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR